

Notice of References Cited	Application/Control No. 10/522,720		Applicant(s)/Patent Under Reexamination KAWAKAMI, TAKASHI	
	Examiner HENOK G. HEYI		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,226,672 B1	05-2001	DeMartin et al.	709/219
*	B	US-6,542,445 B2	04-2003	Ijichi et al.	369/30.08
*	C	US-2003/0167318 A1	09-2003	Robbin et al.	709/221
*	D	US-2004/0213552 A1	10-2004	Kato, Motoki	386/069
*	E	US-2004/0252604 A1	12-2004	Johnson et al.	369/047.22
*	F	US-2005/0273632 A1	12-2005	Kawakami, Takashi	713/193
*	G	US-7,130,251 B1	10-2006	Morohashi, Akihiro	369/47.13
*	H	US-7,237,198 B1	06-2007	Chaney, Jeremy P.	715/730
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003029795 A	01-2003	Japan	SAWAI, MASA HARU	G10L 19/00
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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